

## **General Description**

The WSD1216DN22 is the highest performance trench P-ch MOSFETs with extreme high cell density, which provide excellent RDSON and gate charge for most of the small power switching and load switch applications.

The WSD1216DN22 meet the RoHS and Green Product requirement with full function reliability approved.

#### **Features**

- Advanced high cell density Trench technology
- Super Low Gate Charge
- Excellent Cdv/dt effect decline
- Green Device Available

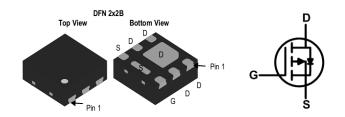
## **Product Summery**

BVDSS	RDSON	ID
-12V	15mΩ	-9.4A

## **Applications**

- High Frequency Point-of-Load Synchronous
   Small power switching for MB/NB/UMPC/VGA
- Networking DC-DC Power System
- Load Switch

## **DFN2X2-6L Pin Configuration**



## **Absolute Maximum Ratings**

Symbol	Parameter	Rating	Units	
$V_{DS}$	Drain-Source Voltage	-12	V	
$V_{GS}$	Gate-Source Voltage	±8	V	
I <sub>D</sub> @T <sub>c</sub> =25℃	Continuous Drain Current, V <sub>GS</sub> @ -4.5V <sup>1</sup>	А		
I <sub>D</sub> @T <sub>c</sub> =70°C	Continuous Drain Current, V <sub>GS</sub> @ -4.5V <sup>1</sup>	-7.5	Α	
I <sub>DM</sub>	300μS Pulsed Drain Current,V <sub>GS</sub> =-4.5V <sup>2</sup>	-37.5	Α	
P <sub>D</sub> @T <sub>A</sub> =25°C	Total Power Dissipation <sup>3</sup> 2.5		W	
T <sub>STG</sub>	Storage Temperature Range -55 to 150		$^{\circ}$	
$T_J$	Operating Junction Temperature Range	-55 to 150	${\mathbb C}$	

# **Thermal Data**

Symbol	Parameter	Тур.	Max.	Unit	
R <sub>0JA</sub>	Thermal Resistance Junction-ambient <sup>1</sup>		80	°C/W	
R <sub>eJC</sub>	Thermal Resistance Junction-Case <sup>1</sup>		28	°C/W	



## Electrical Characteristics (T<sub>J</sub>=25 °C, unless otherwise noted)

Symbol	Parameter	Conditions	Min.	Тур.	Max.	Unit
BV <sub>DSS</sub>	Drain-Source Breakdown Voltage	$V_{GS}$ =0 $V$ , $I_D$ =-250 $u$ A	-12			V
$\triangle BV_{DSS}/\triangle T_{J}$	BVDSS Temperature Coefficient	Reference to 25°C , I <sub>D</sub> =-1mA		-0.01		V/°C
R <sub>DS(ON)</sub>	Static Drain-Source On-Resistance <sup>2</sup>	V <sub>GS</sub> =-4.5V , I <sub>D</sub> =-9.4A		15	20	mΩ
		V <sub>GS</sub> =-2.5V , I <sub>D</sub> =-5.9A		20	27	
V <sub>GS(th)</sub>	Gate Threshold Voltage	V -V 1 - 2500A	-0.4		-0.9	V
$\triangle V_{GS(th)}$	V <sub>GS(th)</sub> Temperature Coefficient	$V_{GS}=V_{DS}$ , $I_D=-250uA$		3.13		mV/℃
	Drain-Source Leakage Current	$V_{DS}$ =-8V , $V_{GS}$ =0V , $T_J$ =25 $^{\circ}$ C			-1	uA
I <sub>DSS</sub>		V <sub>DS</sub> =-8V , V <sub>GS</sub> =0V , T <sub>J</sub> =55℃			-5	uA
I <sub>GSS</sub>	Gate-Source Leakage Current	$V_{GS}$ = $\pm 8V$ , $V_{DS}$ = $0V$			±100	nA
gfs	Forward Transconductance	V <sub>DS</sub> =-5V , I <sub>D</sub> =-1A		16		S
Rg	Gate Resistance	V <sub>DS</sub> =0V , V <sub>GS</sub> =0V , f=1MHz		2		Ω
$Q_g$	Total Gate Charge (-4.5V)	V <sub>DS</sub> =-10V , V <sub>GS</sub> =-4.5V , I <sub>D</sub> =-9.4A		15.5		
$Q_gs$	Gate-Source Charge			2.3		nC
Q <sub>gd</sub>	Gate-Drain Charge			4.6		
T <sub>d(on)</sub>	Turn-On Delay Time	$V_{DD}$ =-10V , $V_{GS}$ =-4.5V , $R_{G}$ =6 $\Omega$ $I_{D}$ =-1A, $R_{L}$ =10 $\Omega$		7		
Tr	Rise Time			12		
T <sub>d(off)</sub>	Turn-Off Delay Time			21		ns
T <sub>f</sub>	Fall Time			12		
Ciss	Input Capacitance	V <sub>DS</sub> =-10V , V <sub>GS</sub> =0V , f=1MHz		1400		
C <sub>oss</sub>	Output Capacitance			297		pF
C <sub>rss</sub>	Reverse Transfer Capacitance			237		

## **Diode Characteristics**

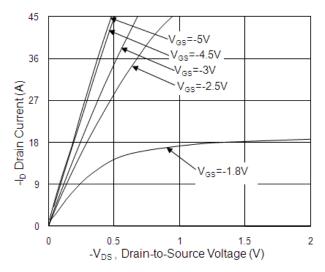
Symbol	Parameter	Conditions	Min.	Тур.	Max.	Unit
Is	Continuous Source Current <sup>1,4</sup>	V <sub>G</sub> =V <sub>D</sub> =0V , Force Current			-2.0	Α
I <sub>SM</sub>	Pulsed Source Current <sup>2,4</sup>				-37.7	Α
V <sub>SD</sub>	Diode Forward Voltage <sup>2</sup>	V <sub>GS</sub> =0V , I <sub>S</sub> =-1A , T <sub>J</sub> =25℃			-1	V
t <sub>rr</sub>	Reverse Recovery Time	lF=-9.4A,dl/dt=100A/µs , Tյ=25℃		26		nS
Qrr	Reverse Recovery Charge			10		nC

#### Note:

- 1.The data tested by surface mounted on a 1 inch² FR-4 board with 2OZ copper, t≦10sec.
- 2.The data tested by pulsed , pulse width  $\,\leq\,$  300us , duty cycle  $\,\leq\,$  2%
- 4. The data is theoretically the same as  $I_D$  and  $I_{DM}$ , in real applications, should be limited by total power dissipation.

**P-Ch MOSFET** 

# **Typical Characteristics**



**Fig.1 Typical Output Characteristics** 

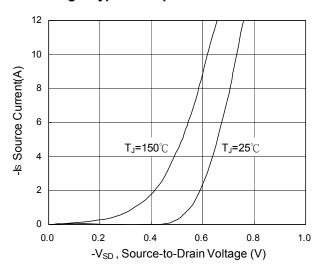


Fig.3 Forward Characteristics Of Reverse

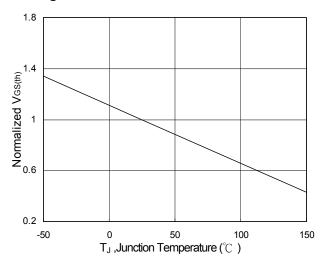


Fig.5 Normalized  $V_{\text{GS(th)}}$  vs.  $T_{\text{J}}$ 

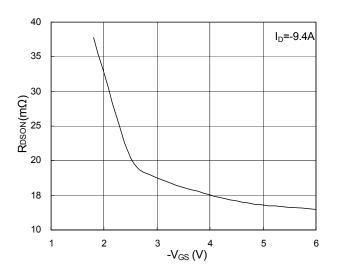


Fig.2 On-Resistance vs. Gate-Source

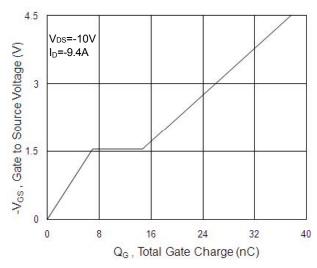


Fig.4 Gate-Charge Characteristics

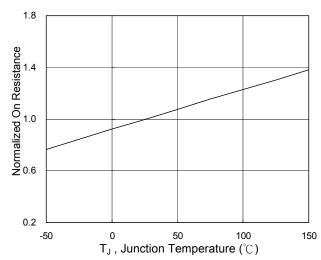
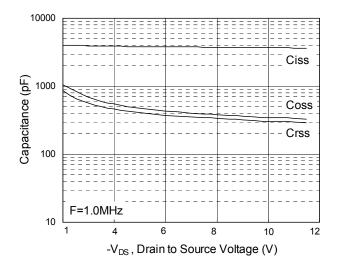


Fig.6 Normalized R<sub>DSON</sub> vs. T<sub>J</sub>





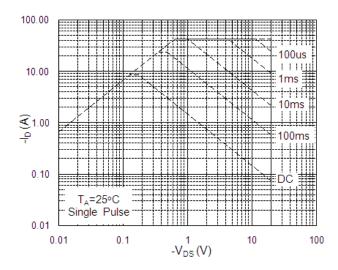


Fig.7 Capacitance

Fig.8 Safe Operating Area

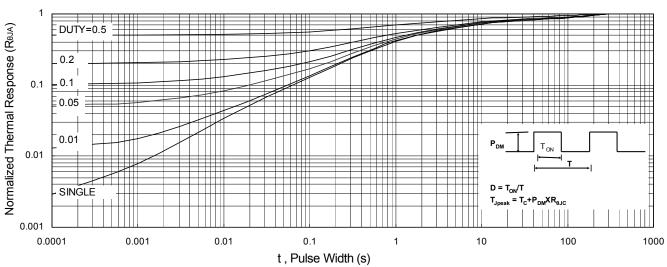
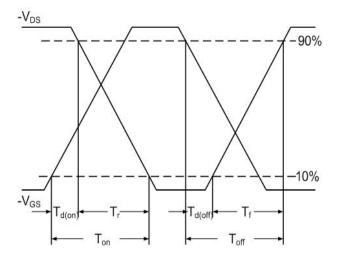


Fig.9 Normalized Maximum Transient Thermal Impedance





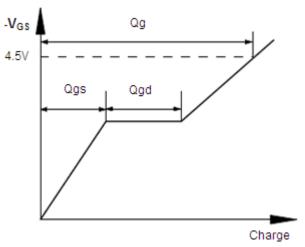


Fig.11 Gate Charge Waveform



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